

PRODUCT/PROCESS CHANGE NOTICE (PCN)								
PCN #: SM-0112-03 DATE: 12/24/01	MEANS OF DISTINGUISHING CHANGED DEVICES:							
Product Affected: 64K, 72K, 128K and 144K Dual-Port Fan (refer to attached List for product details) Manufacturing Location Affected: N/A Date Effective: 3/23/02								
Contact: George Snell								
Title: Quality Assurance Manager	Attachment:: Yes No							
Phone #: (831) 754-4556								
Fax #: (831) 754-4672	Samples: Available upon request. Please contact your local							
E-mail: <u>george.snell@idt.com</u>	Sales Representative for schedule.							
DESCRIPTION AND PURPOSE OF CHANGE:								
■ Wafer Fabrication Process and	s change is to upgrade to a new technology (CMOS9) shrink die. This change is to improve manufacturability allow for expanded product offerings.							
RELIABILITY/QUALIFICATION SUMMARY:								
Qualification testing will verify that there is no change to the prequest	roduct reliability. Qualification details are available upon							
CUSTOMER ACKNOWLEDGMENT OF RECEIPT: IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable. IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.								
Customer:	☐ Approval for shipments prior to effective date.							
Name/Date:	E-Mail Address:							
Title:	Phone# /Fax#:							
CUSTOMER COMMENTS:								
IDT ACKNOWLEDGMENT OF RECEIPT:								
RECD. BY:	DATE:							

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PCN Summary

PCN Type: Mask/Design Change for Die Shrink

Commodity Memory

Forecast or Execute Execute

Planned or Unplanned Planned

Data Sheet Change N/A

Detail of Change The base device for each part is detailed on the attached product detail sheet. The new base

device for future products listed on this PCN will be 7025 "U". This product redesign will allow for

IDT to expand product offerings and upgrade technology. The Hillsboro, Oregon Wafer

Fabrication Facility has been previously qualified for CMOS 9 processing.

	Current Di	e Revision	Planned Change		
Base Device / Die Revision	7025V	70V25V	7025U	70V25U	
Wafer Fab Facility	Salinas, CA	Salinas, CA	Salinas, CA Hillsboro, OR		
Wafer Fab Technology	CMOS 8	CMOS 8	CMOS 9	CMOS 9	
Wafer Size	6 inch	6 inch	8 inch	8 inch	
# Poly Layers	2	2	3	3	
# Metal Layers	2	2	2	2	
Minumum Feature Size / µm	0.6	0.4	0.55	0.32	
Die Dimensions/(K sq mils)	39.6K	39.6K	32K	32K	

Conversion schedule: Shown on attached Product listing on page 4.

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Qualification Plan:

Expected Completion Date

Test Vehicles		1/31/2002	3/4/2002	5/4/2002	6/15/2002
70V25U (3.3V) & 7025U (5V)	Required Sample / # Fails	LOT #1 3.3V	LOT #2 3.3V	LOT #1 5V	LOT #2 5V
Operating Life Test: Dynamic @+135°C, Vcc=6V for 750 hours or Vcc=4V for 750 hours	116/0				
High Temp. Storage Life Test (Unbiased, 1000 hours @+150°C)	77 / 0				
Bake & Ballshear Test @ 200°C / 4 ball bonds per device	5/0				
Temperature Cycling: (-65°C to +150°C, 500 cycles)	45 / 0				
HAST: (Biased, 100 Hrs. @+130°C, +85%RH, 3 Atm.)	45 / 0				
Autoclave: (Unbiased, 2 Atm Saturated Steam, +121°C, 168 Hrs)	45 / 0				
ESD Human Body Model	6/0				
ESD Charged Device Model	6/0				
Latch up: (Tested to 2X Vcc)	10/0				

Tests are completed for unshaded areas. Product released is based on qualification of initial lot.



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IDT7025 Family of Parts										
			New							
	Old	New	Speed						Sample	Production
Part Number	Rev.	Rev.	Grades	Interface	Vcc	Bus	Depth	Density	Availability	Availability
IDT7035S/L	V	U	10, 12 ns	Async	5	x18	8K	144K	March 2002	May 2002
IDT7034S/L	V	U	10, 12 ns	Async	5	x18	4K	72K	March 2002	May 2002
IDT7025S/L	>	U	10, 12 ns	Async	5	x16	8K	128K	March 2002	May 2002
IDT7024S/L	٧	U	10, 12 ns	Async	5	x16	4K	64K	March 2002	May 2002
IDT7016S/L	V	U	10, 12 ns	Async	5	х9	16K	144K	April 2002	May 2002
IDT7015S/L	>	U	10, 12 ns	Async	5	x9	8K	72K	April 2002	May 2002
IDT7016S/L	W	U	10, 12 ns	Async	5	х9	16K	144K	April 2002	May 2002
IDT7015S/L	W	U	10, 12 ns	Async	5	x9	8K	72K	April 2002	May 2002
IDT7006S/L	٧	U	10, 12 ns	Async	5	х8	16K	128K	April 2002	May 2002
IDT7005S/L	٧	U	10, 12 ns	Async	5	х8	8K	64K	April 2002	May 2002
IDT70V35S/L	V	U	10, 12 ns	Async	3.3	x18	8K	144K	January 2002	February 2002
IDT70V34S/L	٧	U	10, 12 ns	Async	3.3	x18	4K	72K	January 2002	February 2002
IDT70V25S/L	>	U	10, 12 ns	Async	3.3	x16	8K	128K	January 2002	February 2002
IDT70V24S/L	V	U	10, 12 ns	Async	3.3	x16	4K	64K	January 2002	February 2002
IDT70V06S/L	V	U	10, 12 ns	Async	3.3	х8	16K	128K	February 2002	March 2002
IDT70V05S/L	V	U	10, 12 ns	Async	3.3	x8	8K	64K	February 2002	March 2002